

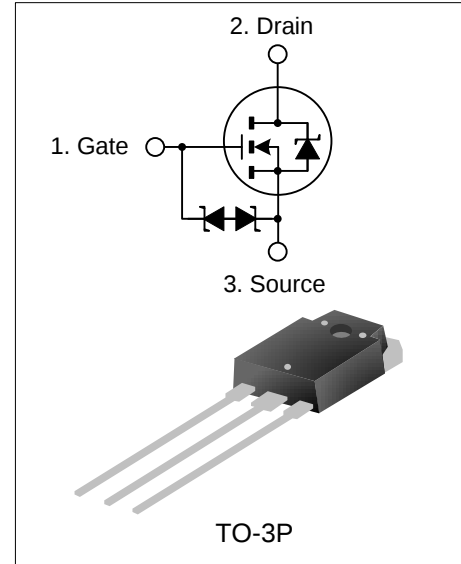
25A, 500V N-CHANNEL MOSFET

DESCRIPTION

SVF25NE50PN is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell™ structure VDMOS technology. The improved planar stripe cell and the improved guard ring terminal have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are widely used in AC-DC power suppliers, DC-DC converters and H-bridge PWM motor drivers.

FEATURES

- 25A, 500V, $R_{DS(on)}(typ.)=0.18\Omega@V_{GS}=10V$
- Low gate charge
- Low C_{rss}
- Fast switching
- Improved dv/dt capability



ORDERING INFORMATION

Part No.	Package	Marking	Hazardous Substance Control	Packing Type
SVF25NE50PN	TO-3P	25NE50	Pb free	Tube

ABSOLUTE MAXIMUM RATINGS (UNLESS OTHERWISE NOTED, T_C=25°C)

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		V _{DS}	500	V
Gate-Source Voltage		V _{GS}	±30	V
Drain Current	T _C =25°C	I _D	25.0	A
	T _C =100°C		15.81	
Drain Current Pulsed		I _{DM}	100	A
Power Dissipation (T _C =25°C)		P _D	260	W
-Derate above 25°C			2.08	W/°C
Single Pulsed Avalanche Energy (Note 1)		E _{AS}	2560	mJ
Operation Junction Temperature Range		T _J	-55~+150	°C
Storage Temperature Range		T _{stg}	-55~+150	°C

THERMAL CHARACTERISTICS

Characteristics	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Case	R _{θJC}	0.48	°C/W
Thermal Resistance, Junction-to-Ambient	R _{θJA}	50	°C/W

ELECTRICAL CHARACTERISTICS (UNLESS OTHERWISE NOTED, T_C=25°C)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	B _{VDS}	V _{GS} =0V, I _D =250μA	500	--	--	V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =500V, V _{GS} =0V	--	--	1.0	μA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =±30V, V _{DS} =0V	--	--	±100	μA
Gate Threshold Voltage	V _{GS(th)}	V _{GS} = V _{DS} , I _D =250μA	2.0	--	4.0	V
On State Resistance	R _{DS(on)}	V _{GS} =10V, I _D =12.5A	--	0.18	0.27	Ω
Input Capacitance	C _{iss}	V _{DS} =25V, V _{GS} =0V, f=1.0MHZ	--	3466.5	--	pF
Output Capacitance	C _{oss}		--	413.0	--	
Reverse Transfer Capacitance	C _{rss}		--	9.5	--	
Turn-on Delay Time	t _{d(on)}	V _{DD} =250V, V _{GS} =10V, R _G =25Ω, I _D =25.0A (Note2,3)	--	54.1	--	ns
Turn-on Rise Time	t _r		--	76.1	--	
Turn-off Delay Time	t _{d(off)}		--	165.4	--	
Turn-off Fall Time	t _f		--	74.4	--	
Total Gate Charge	Q _g	V _{DD} =400V, V _{GS} =10V, I _D =25.0A (Note 2,3)	--	51.83	--	nC
Gate-Source Charge	Q _{gs}		--	16.22	--	
Gate-Drain Charge	Q _{gd}		--	14.49	--	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Source Current	I_S	Integral Reverse P-N Junction Diode in the MOSFET	--	--	25.0	A
Pulsed Source Current	I_{SM}		--	--	100.0	
Diode Forward Voltage	V_{SD}	$I_S=25.0A, V_{GS}=0V$	--	--	1.4	V
Reverse Recovery Time	T_{rr}	$I_S=25.0A, V_{GS}=0V, dI_F/dt=100A/\mu S$ (Note2)	--	626.13	--	ns
Reverse Recovery Charge	Q_{rr}		--	8.94	--	μC

Notes:

1. $L=30mH, I_{AS}=12A, V_{DD}=100V, R_G=25\Omega$, starting $T_J=25^\circ C$;
2. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$;
3. Essentially independent of operating temperature.

TYPICAL CHARACTERISTICS

Figure 1. On-Region Characteristics

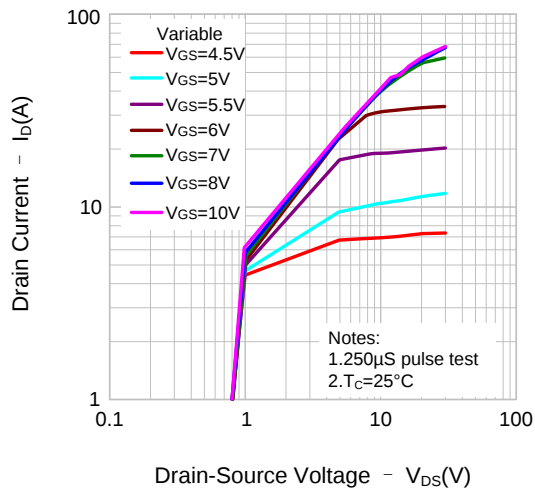


Figure 2. Transfer Characteristics

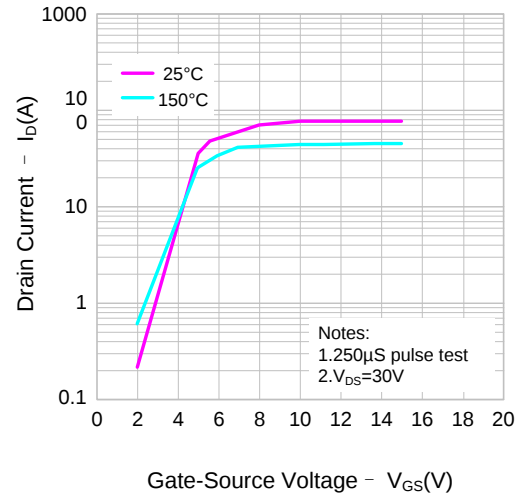


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

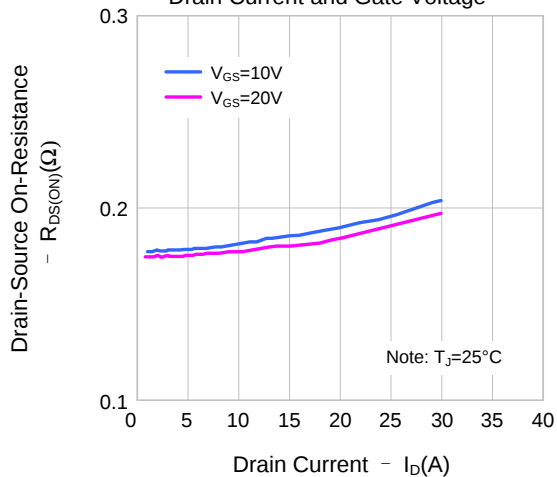
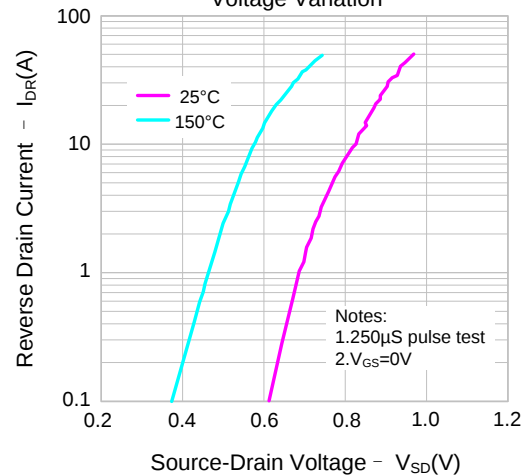


Figure 4. Source-Drain Diode Forward Voltage Variation



TYPICAL CHARACTERISTICS

Figure 5. Capacitance Characteristics

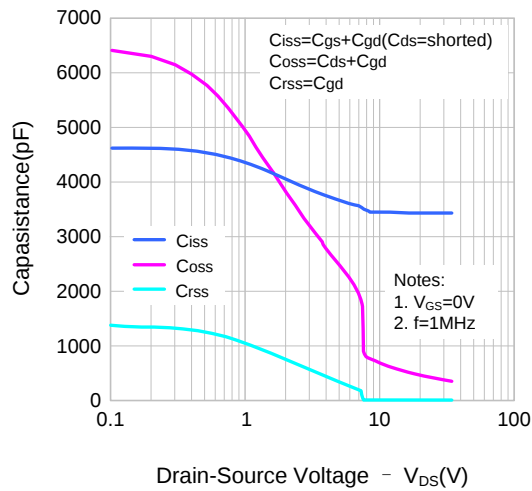


Figure 6. Gate Charge Characteristics

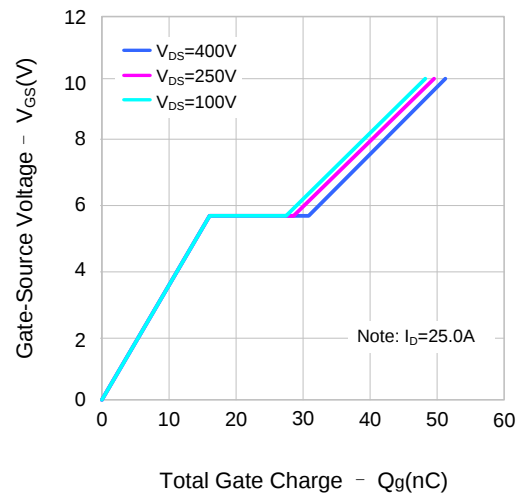


Figure 7. Breakdown Voltage Variation vs. Temperature

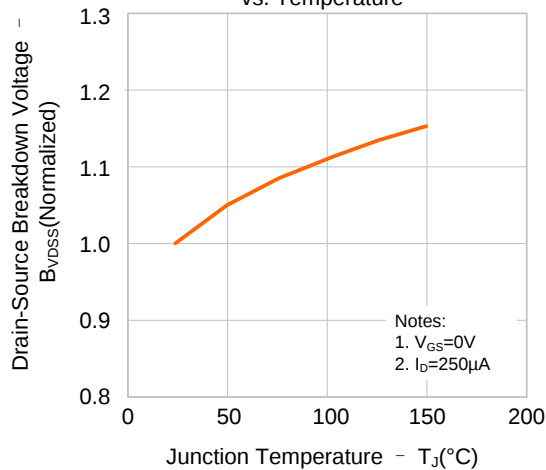


Figure 8. On-resistance Variation vs. Temperature

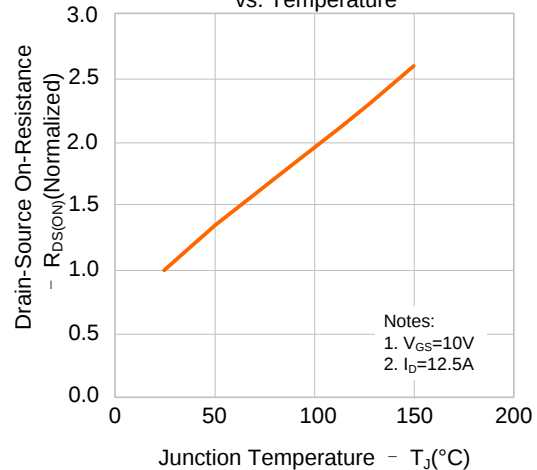


Figure 9. Max. Safe Operating Area

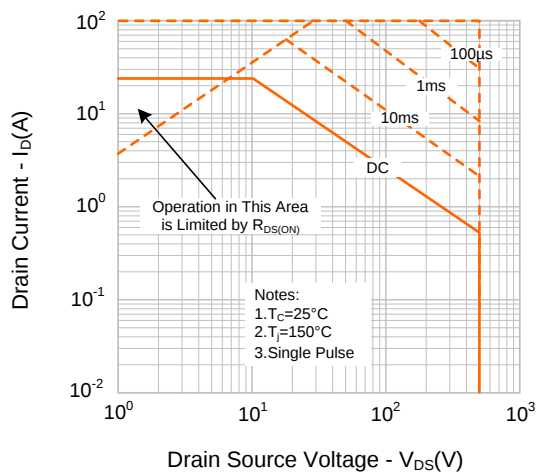
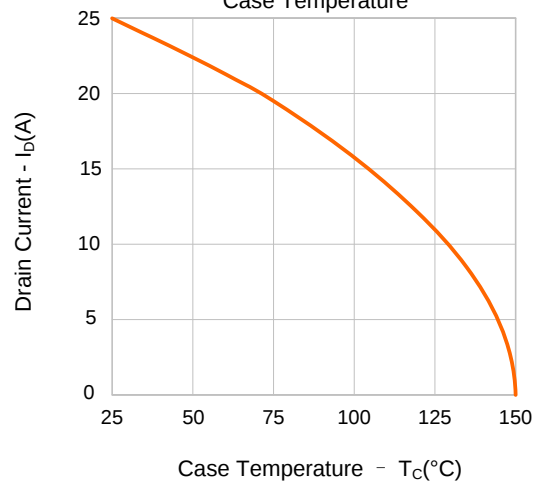
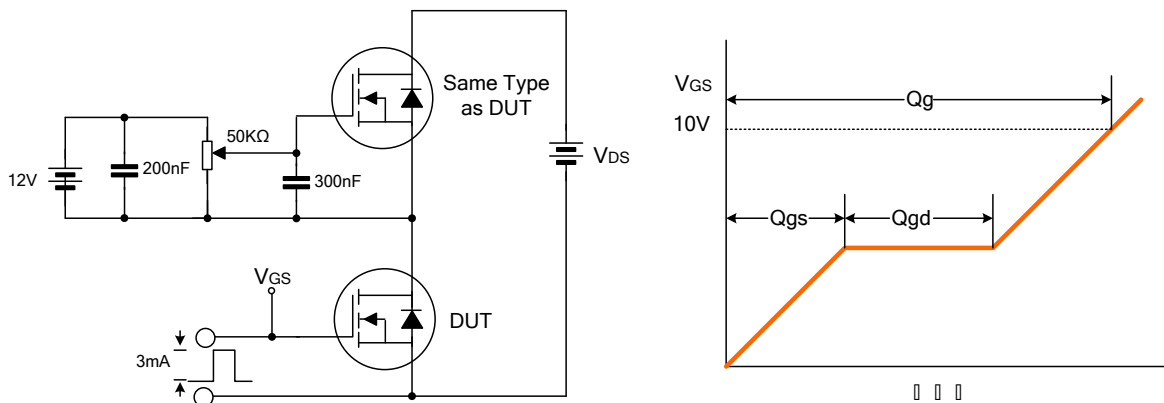


Figure 10. Maximum Drain Current vs. Case Temperature

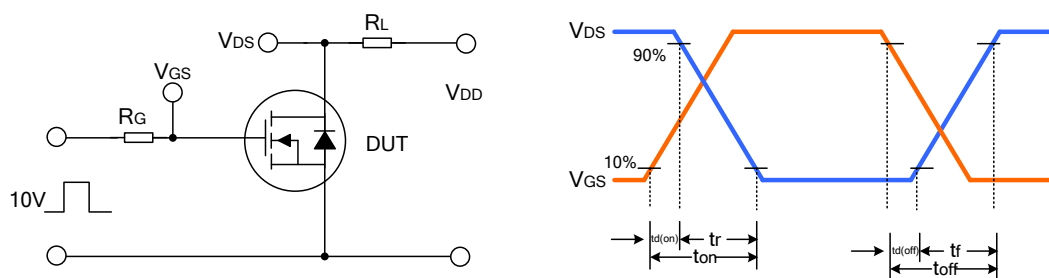


TYPICAL TEST CIRCUIT

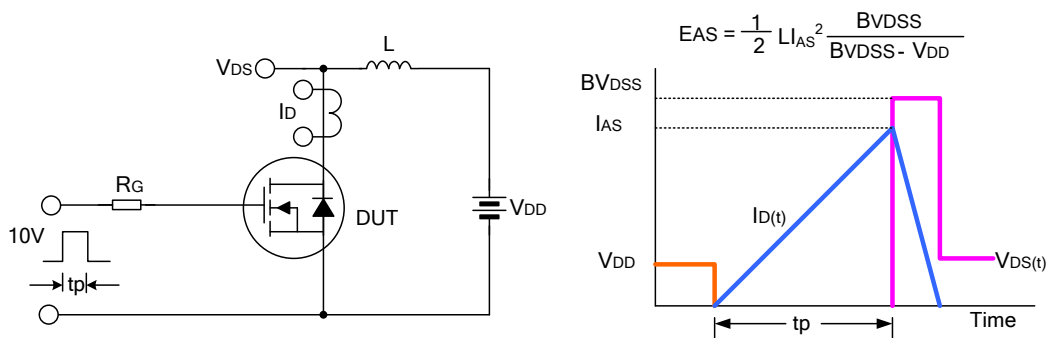
Gate Charge Test Circuit & Waveform



Switching Test Circuit & Waveform



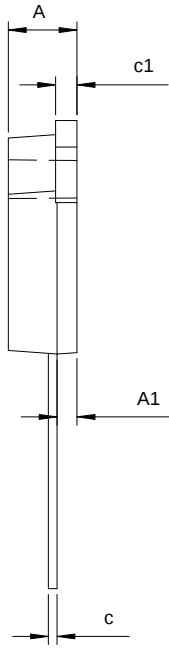
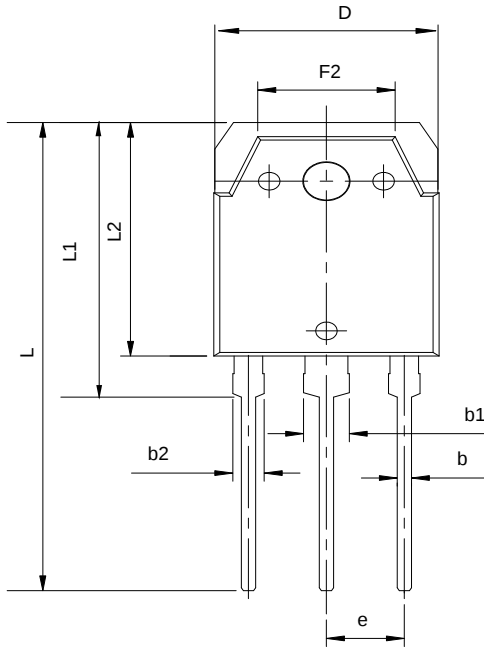
EAS Test Circuit & Waveform



PACKAGE OUTLINE

TO-3P

UNIT: mm



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	4.4	—	5.2
C1	1.2	—	1.8
A1	1.2	—	2.0
b	0.7	1.0	1.3
b1	2.7	3.0	3.3
b2	1.7	2.0	2.3
D	15.0	15.5	16.0
C	0.4	0.6	0.8
F2	8.5	—	10.0
e	5.45 TYP		
L1	22.6	—	23.6
L	39.0	—	41.5
L2	19.5	—	21.0

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Rev.: 1.1

Revision History:

1. Deleted NOMENCLATURE
 2. Modify Important notice
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Rev.: 1.0

Revision History:

1. First release
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